Superior Magnetics Since 1979

CMOQ-4

LINE OUTPUT TRANSFORMER
Quadfilar Windings

- **Excellent bandwidth -0.1 dB at 200 kHz**
- **Rs=50Ω 80% Nickel ("HiNi") laminations**
- **Distortion <0.05% typ at 20 Hz, Rs=150Ω HiNi**
- **+15 dBm at 20 Hz, 1% THD+N Rs≤150Ω**
- **Phase Shift -3.5° at 20 kHz, Rs=150Ω**
- **Excellent coupling**

The CineMag CMOQ-4 output transformer uses quadfilar construction techniques. This four-winding transformer delivers good coupling between windings as well as excellent bandwidth. It is available both with 80% Nickel ("HiNi") and 50% Nickel/50% Steel laminations. It can be driven with source impedances of up to 600 Ω. As with all line drivin g devices, the amplifier feeding it shou ld be capa ble of clea nly delivering the power required to reach maximum operating level. See AN-102.

CMOQ-4H / CMOQ-4L PC mounting available on request.

Parameter	Conditions	Typ
Turns Ratio		1 : 1.00
Input Impedance, Zi	20 Hz to 20 kHz, 0 dBu Test Circuit 3	657Ω
Voltage Gain	1 kHz HiNi Core, Rs=150 Test Circuit 1 1 kHz 50% Nickel/50% Steel Core, Rs=150	-3.13 dB -3.15 dB
Distortion (THD+N%)	1 kHz, +9 dBu, Rs=150 HiNi Test Circuit 1 1 kHz, +9 dBu, Rs=150 50%Ni/50% Steel	0.0005% 0.0009%
Max 20 Hz input level	1.0% THD+N, Rs≤150 HiNi Test Circuit 1 1.0% THD+N, Rs≤150 50% Ni 50% Steel	+16 dB +16 dB
Response, ref 1 kHz	20 Hz Rs=150Ω HiNi Test Circuit 1 20 kHz Rs=150Ω HiNi Test Circuit 1 200 kHz Rs=150Ω HiNi Test Circuit 1	-0.05 dB -0.02 dB -1.2 dB
Phase Shift at 20Hz Phase Shift at 20 kHz	Referenced to source generator Test Circuit 1	+3° -3.5°
CMRR	60 Hz Test Circuit 4 per IEEE Std 389-1996 ¶19 1 kHz Test Circuit 4 per IEEE Std 389-1996 ¶19	92 dB 93 dB
Output CMRR	60 Hz Test Circuit 2 1 kHz Test Circuit 2	82 dB 92 dB
Operating Temp Range	Operation and storage	0° C Min 70° C Max

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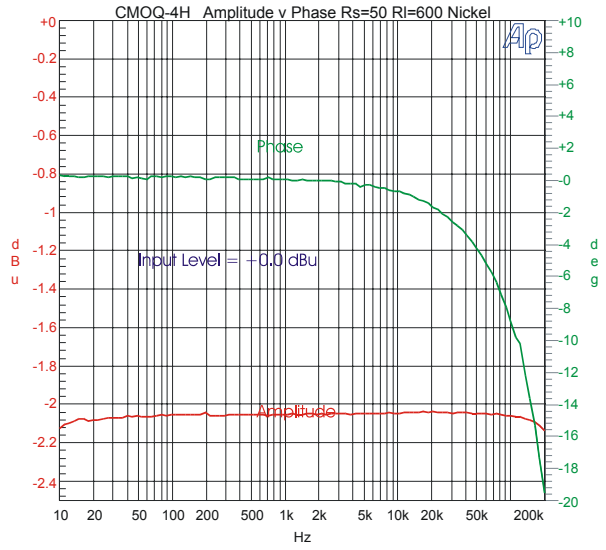
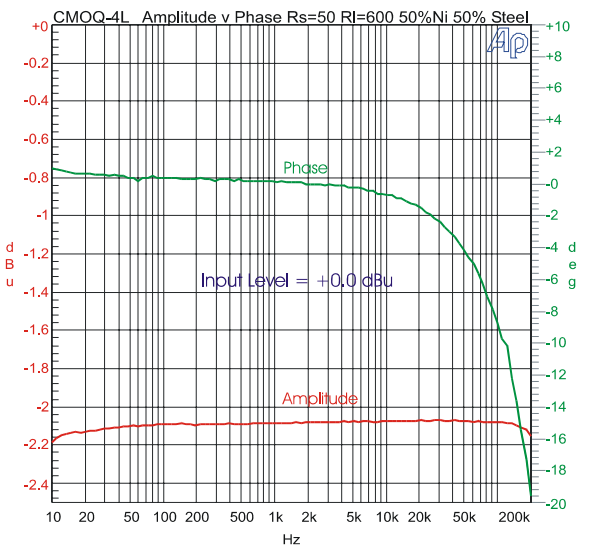
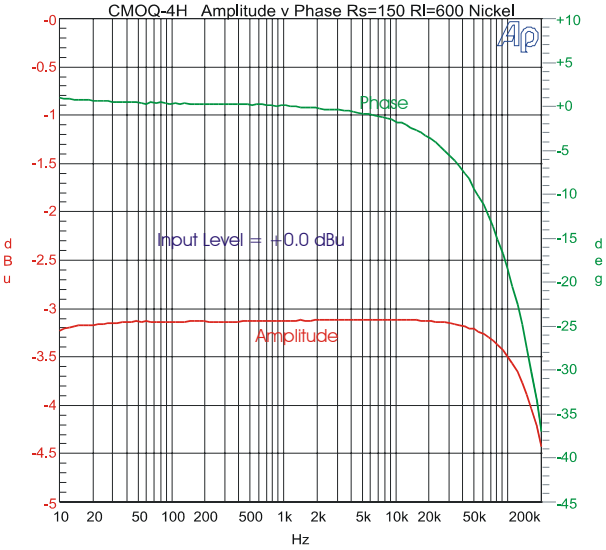
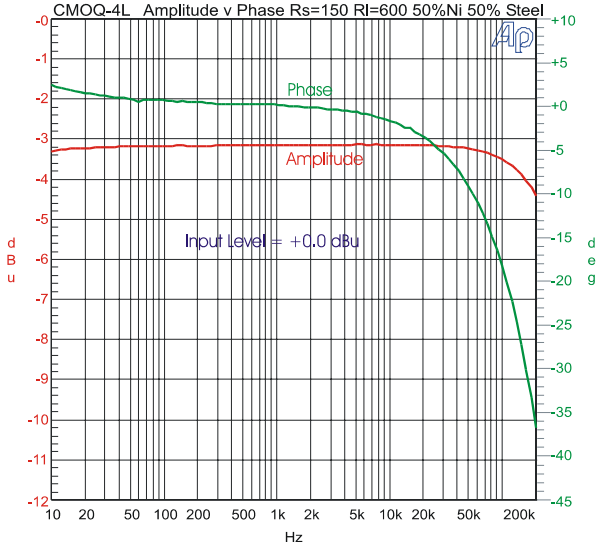
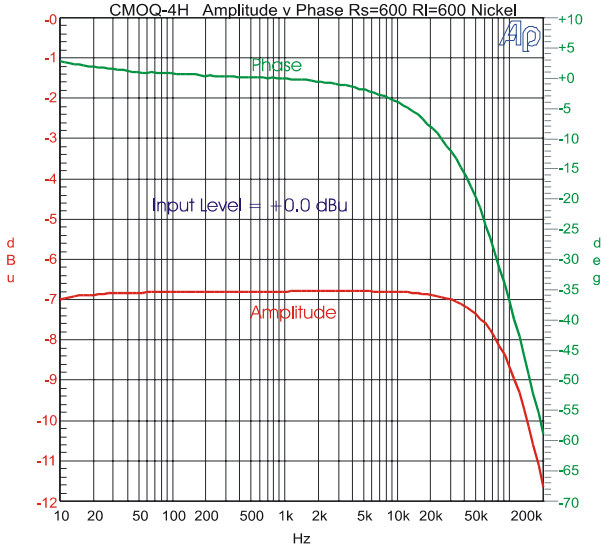
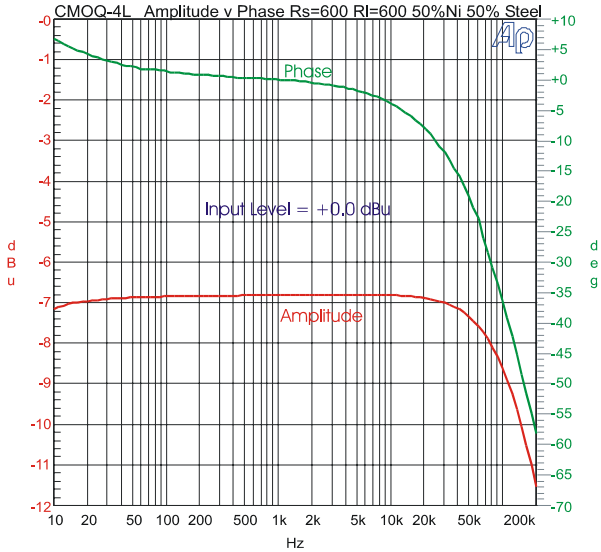


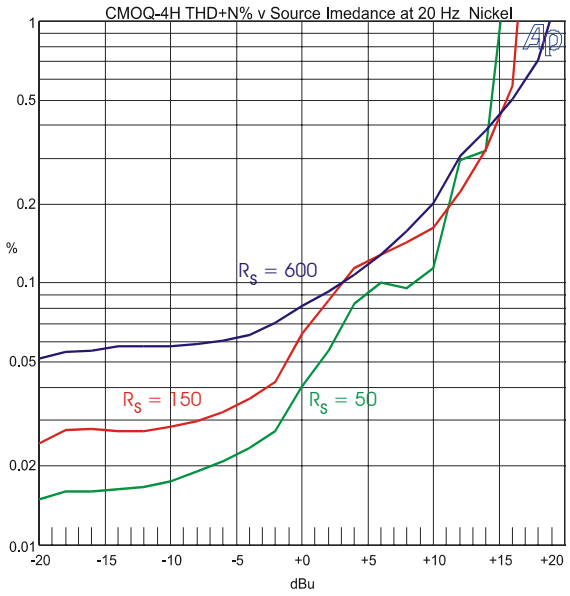


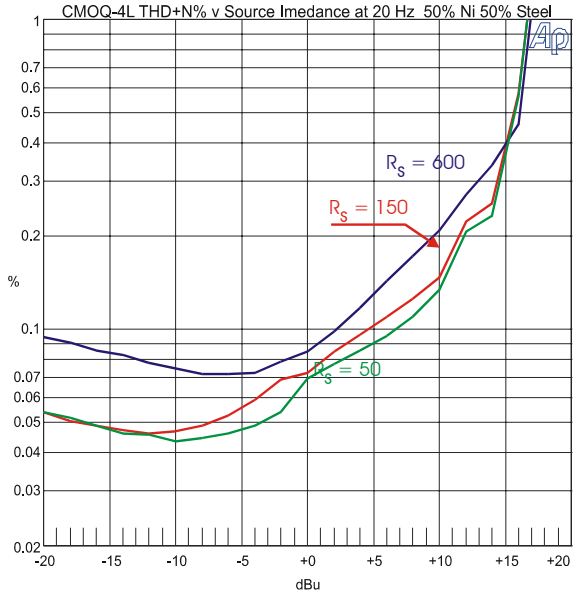


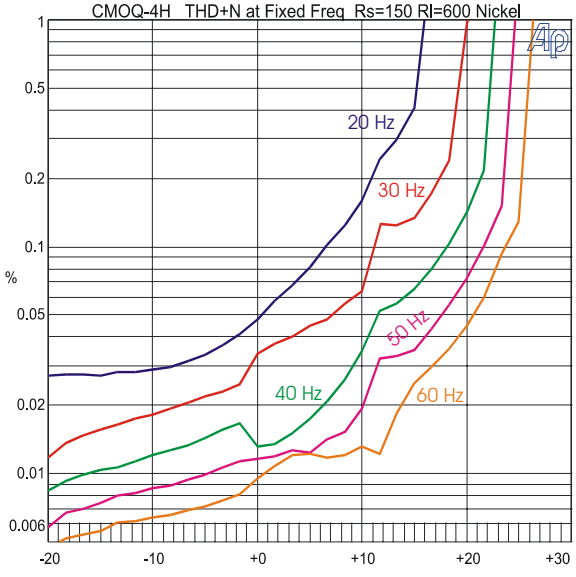


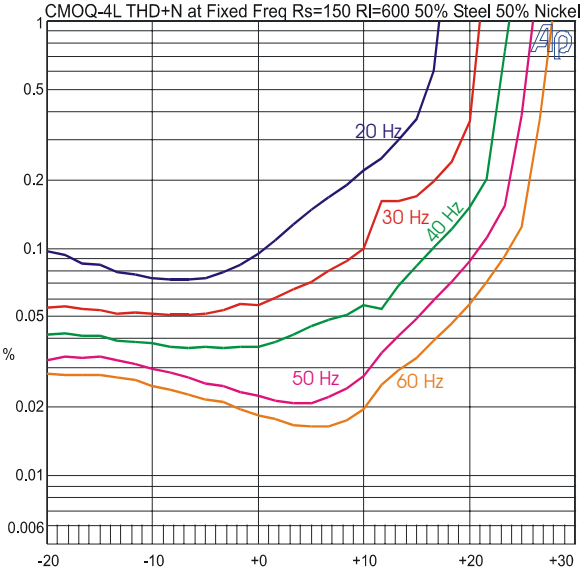


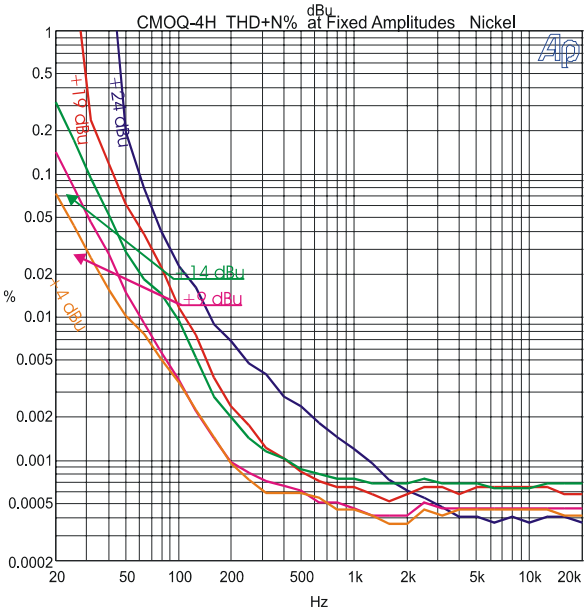


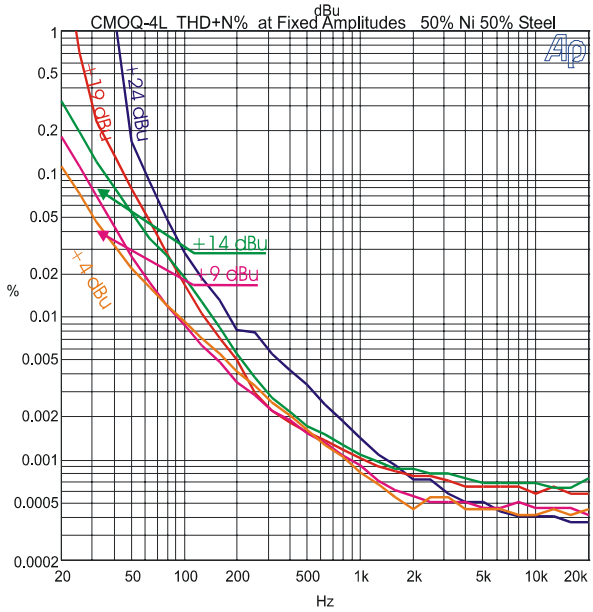


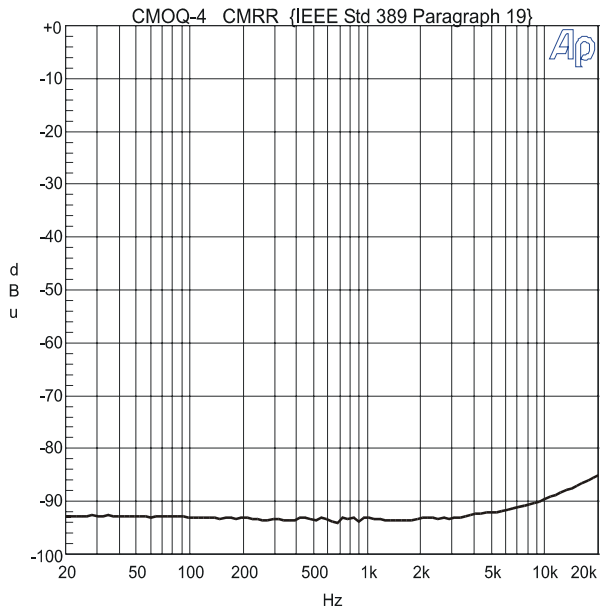


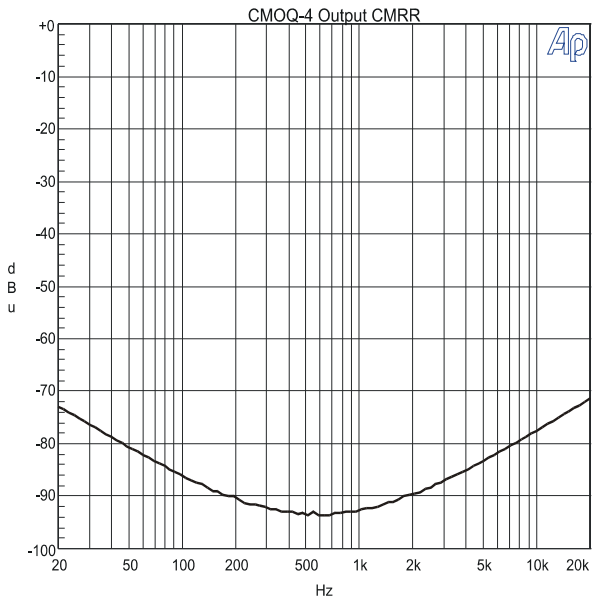


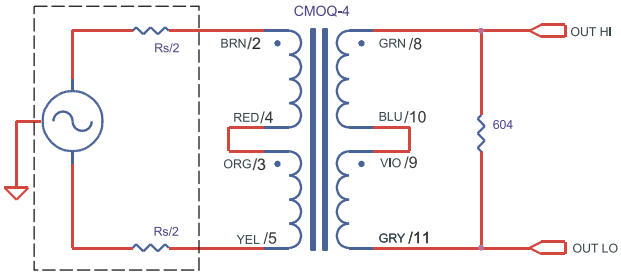




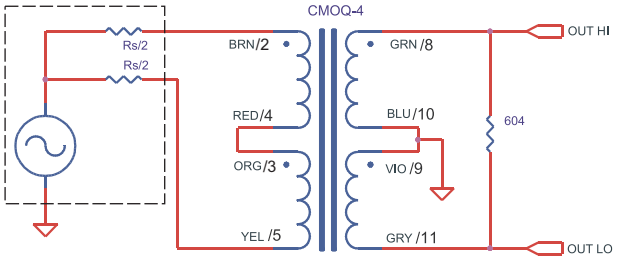








TEST CIRCUIT 1



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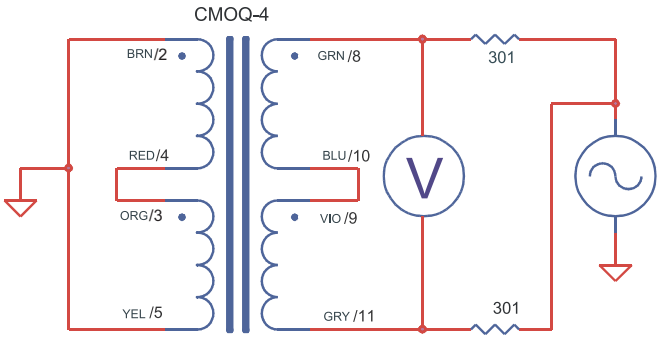
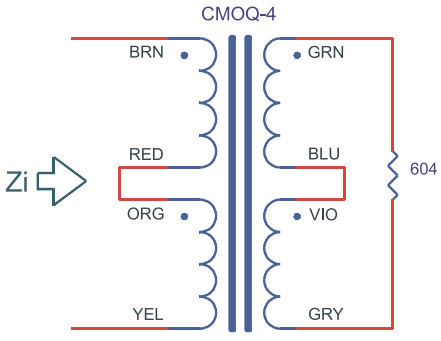


TEST CIRCUIT 3



TEST CIRCUIT 4

NOTES:

1. All graphs generated from one (1) randomly chosen device. No statistical averaging or weighting. Data from one sweep.
2. R_L = 604 unless otherwise noted.